

# Notice of References Cited

Application No.  
08/889,440

Applicant(s)  
Takeuchi et al.

Examiner  
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Page 1 of 1

## U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A					
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## FOREIGN PATENT DOCUMENTS

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## NON-PATENT DOCUMENTS

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
U	Husinsky et al.; "Fundamental aspects of SNMS for thin film characterization: experimental studies and computer simulations"; Thin Solid Films; pp. 289-309	1/1996
V		
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X		